



## 3.3V CMOS OCTAL BUFFER/ DRIVER WITH 3-STATE OUTPUTS AND BUS-HOLD

**IDT74ALVCH244**

### FEATURES:

- 0.5 MICRON CMOS Technology
- Typical  $t_{sk(o)}$  (Output Skew) < 250ps
- ESD > 2000V per MIL-STD-883, Method 3015; > 200V using machine model (C = 200pF, R = 0)
- $V_{CC} = 3.3V \pm 0.3V$ , Normal Range
- $V_{CC} = 2.7V$  to  $3.6V$ , Extended Range
- $V_{CC} = 2.5V \pm 0.2V$
- CMOS power levels (0.4 $\mu$  W typ. static)
- Rail-to-Rail output swing for increased noise margin
- Available in QSOP, SOIC, SSOP, and TSSOP packages

### DRIVE FEATURES:

- High Output Drivers:  $\pm 24mA$
- Suitable for Heavy Loads

### APPLICATIONS:

- 3.3V high speed systems
- 3.3V and lower voltage computing systems

### DESCRIPTION:

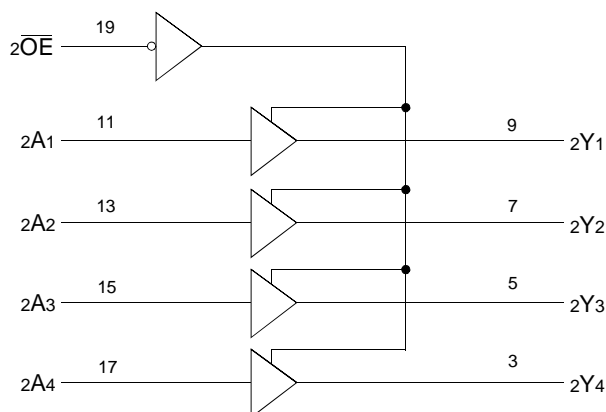
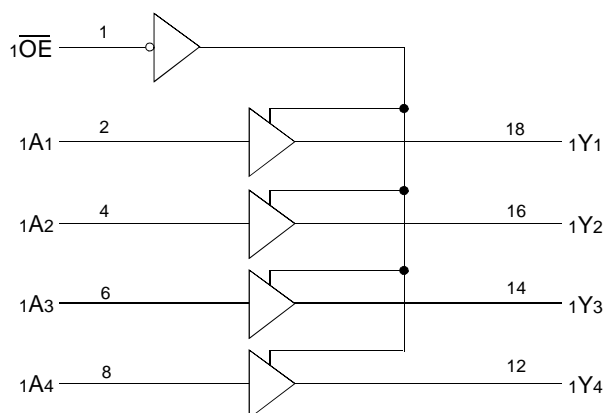
The ALVCH244 octal buffer/driver is built using advanced dual metal CMOS technology. The ALVCH244 is organized as two 4-bit line drivers with separate output-enable ( $\overline{OE}$ ) inputs. When  $\overline{OE}$  is low, the device passes data from the A inputs to the Y outputs. When  $\overline{OE}$  is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

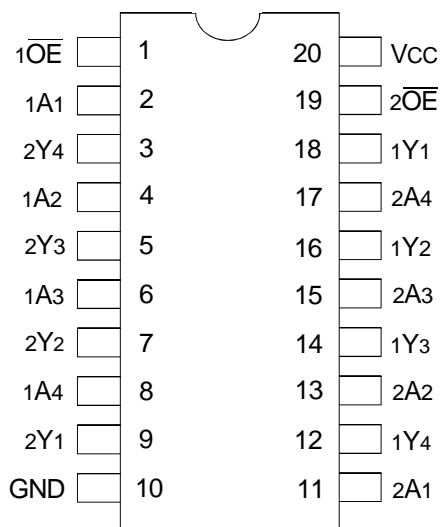
The ALVCH244 has been designed with a  $\pm 24mA$  output driver. This driver is capable of driving a moderate to heavy load while maintaining speed performance.

The ALVCH244 has a "bus-hold" which retains the inputs' last state whenever the input bus goes to a high impedance. This prevents floating inputs and eliminates the need for pull-up/down resistors.

## FUNCTIONAL BLOCK DIAGRAM



## PIN CONFIGURATION



QSOP/ SOIC/ SSOP/ TSSOP  
TOPVIEW

## ABSOLUTE MAXIMUM RATINGS<sup>(1)</sup>

Symbol	Description	Max	Unit
VTERM <sup>(2)</sup>	Terminal Voltage with Respect to GND	-0.5 to +4.6	V
VTERM <sup>(3)</sup>	Terminal Voltage with Respect to GND	-0.5 to V <sub>CC</sub> +0.5	V
TSTG	Storage Temperature	-65 to +150	°C
I <sub>OUT</sub>	DC Output Current	-50 to +50	mA
I <sub>IK</sub>	Continuous Clamp Current, V <sub>I</sub> < 0 or V <sub>I</sub> > V <sub>CC</sub>	±50	mA
I <sub>OK</sub>	Continuous Clamp Current, V <sub>O</sub> < 0	-50	mA
I <sub>CC</sub> I <sub>SS</sub>	Continuous Current through each V <sub>CC</sub> or GND	±100	mA

### NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- V<sub>CC</sub> terminals.
- All terminals except V<sub>CC</sub>.

## CAPACITANCE (T<sub>A</sub> = +25°C, F = 1.0MHz)

Symbol	Parameter <sup>(1)</sup>	Conditions	Typ.	Max.	Unit
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 0V	5	7	pF
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 0V	7	9	pF
C <sub>I/O</sub>	I/O Port Capacitance	V <sub>IN</sub> = 0V	7	9	pF

### NOTE:

- As applicable to the device type.

## PIN DESCRIPTION

Pin Names	Description
$\overline{xOE}$	3-State Output Enable Inputs (Active LOW)
xAx	Data Inputs <sup>(1)</sup>
xYx	3-State Outputs

### NOTE:

- These pins have "Bus-Hold". All other pins are standard inputs, outputs, or I/Os.

## FUNCTION TABLE (EACH BUFFER)<sup>(1)</sup>

Inputs		Outputs
$\overline{xOE}$	xAx	xYx
L	H	H
L	L	L
H	X	Z

### NOTE:

- H = HIGH Voltage Level  
L = LOW Voltage Level  
X = Don't Care  
Z = High Impedance

## DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Operating Condition:  $T_A = -40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$

Symbol	Parameter	Test Conditions		Min.	Typ. <sup>(1)</sup>	Max.	Unit
V <sub>IH</sub>	Input HIGH Voltage Level	V <sub>CC</sub> = 2.3V to 2.7V		1.7	—	—	V
		V <sub>CC</sub> = 2.7V to 3.6V		2	—	—	
V <sub>IL</sub>	Input LOW Voltage Level	V <sub>CC</sub> = 2.3V to 2.7V		—	—	0.7	V
		V <sub>CC</sub> = 2.7V to 3.6V		—	—	0.8	
I <sub>IH</sub>	Input HIGH Current	V <sub>CC</sub> = 3.6V	V <sub>I</sub> = V <sub>CC</sub>	—	—	±5	μA
I <sub>IL</sub>	Input LOW Current	V <sub>CC</sub> = 3.6V	V <sub>I</sub> = GND	—	—	±5	μA
I <sub>OZH</sub> I <sub>OZL</sub>	High Impedance Output Current (3-State Output pins)	V <sub>CC</sub> = 3.6V	V <sub>O</sub> = V <sub>CC</sub>	—	—	±10	μA
			V <sub>O</sub> = GND	—	—	±10	
V <sub>IK</sub>	Clamp Diode Voltage	V <sub>CC</sub> = 2.3V, I <sub>IN</sub> = -18mA		—	-0.7	-1.2	V
V <sub>H</sub>	Input Hysteresis	V <sub>CC</sub> = 3.3V		—	100	—	mV
I <sub>CCL</sub> I <sub>CCH</sub> I <sub>CCZ</sub>	Quiescent Power Supply Current	V <sub>CC</sub> = 3.6V V <sub>IN</sub> = GND or V <sub>CC</sub>		—	0.1	40	μA
ΔI <sub>CC</sub>	Quiescent Power Supply Current Variation	One input at V <sub>CC</sub> - 0.6V, other inputs at V <sub>CC</sub> or GND		—	—	750	μA

**NOTE:**

1. Typical values are at V<sub>CC</sub> = 3.3V, +25°C ambient.

## BUS-HOLD CHARACTERISTICS

Symbol	Parameter <sup>(1)</sup>	Test Conditions		Min.	Typ. <sup>(2)</sup>	Max.	Unit
I <sub>BHH</sub> I <sub>BHL</sub>	Bus-Hold Input Sustain Current	V <sub>CC</sub> = 3V	V <sub>I</sub> = 2V	-75	—	—	μA
			V <sub>I</sub> = 0.8V	75	—	—	
I <sub>BHH</sub> I <sub>BHL</sub>	Bus-Hold Input Sustain Current	V <sub>CC</sub> = 2.3V	V <sub>I</sub> = 1.7V	-45	—	—	μA
			V <sub>I</sub> = 0.7V	45	—	—	
I <sub>BHHO</sub> I <sub>BHLO</sub>	Bus-Hold Input Overdrive Current	V <sub>CC</sub> = 3.6V	V <sub>I</sub> = 0 to 3.6V	—	—	±500	μA

**NOTES:**

1. Pins with Bus-Hold are identified in the pin description.
2. Typical values are at V<sub>CC</sub> = 3.3V, +25°C ambient.

## OUTPUT DRIVE CHARACTERISTICS

Symbol	Parameter	Test Conditions <sup>(1)</sup>		Min.	Max.	Unit
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> = 2.3V to 3.6V	I <sub>OH</sub> = - 0.1mA	V <sub>CC</sub> - 0.2	—	V
		V <sub>CC</sub> = 2.3V	I <sub>OH</sub> = - 6mA	2	—	
		V <sub>CC</sub> = 2.3V	I <sub>OH</sub> = - 12mA	1.7	—	
		V <sub>CC</sub> = 2.7V		2.2	—	
		V <sub>CC</sub> = 3V		2.4	—	
		V <sub>CC</sub> = 3V		I <sub>OH</sub> = - 24mA	2	
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = 2.3V to 3.6V	I <sub>OL</sub> = 0.1mA	—	0.2	V
		V <sub>CC</sub> = 2.3V	I <sub>OL</sub> = 6mA	—	0.4	
			I <sub>OL</sub> = 12mA	—	0.7	
		V <sub>CC</sub> = 2.7V	I <sub>OL</sub> = 12mA	—	0.4	
		V <sub>CC</sub> = 3V	I <sub>OL</sub> = 24mA	—	0.55	

- NOTE:**  
1. V<sub>IH</sub> and V<sub>IL</sub> must be within the min. or max. range shown in the DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE table for the appropriate V<sub>CC</sub> range. T<sub>A</sub> = - 40°C to + 85°C.

## OPERATING CHARACTERISTICS, T<sub>A</sub> = 25°C

Symbol	Parameter	Test Conditions	V <sub>CC</sub> = 2.5V ± 0.2V	V <sub>CC</sub> = 3.3V ± 0.3V	Unit
			Typical	Typical	
CPD	Power Dissipation Capacitance Outputs enabled	C <sub>L</sub> = 0pF, f = 10Mhz	22	28	pF
CPD	Power Dissipation Capacitance Outputs disabled		1.5	4	

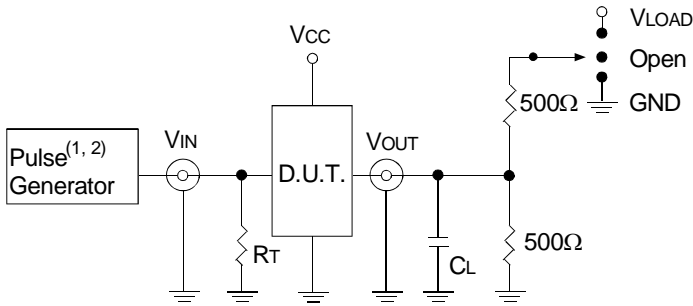
## SWITCHING CHARACTERISTICS<sup>(1)</sup>

Symbol	Parameter	V <sub>CC</sub> = 2.5V ± 0.2V		V <sub>CC</sub> = 2.7V		V <sub>CC</sub> = 3.3V ± 0.3V		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>PLH</sub>	Propagation Delay	1	3.1	—	3.1	1.1	2.8	ns
t <sub>PHL</sub>	xAx to xYx							
t <sub>PZH</sub>	Output Enable Time	1.5	5.4	—	5.3	1.5	4.5	ns
t <sub>PZL</sub>	xOE to xYx							
t <sub>PHZ</sub>	Output Disable Time	1	4.1	—	4.4	1.7	4.2	ns
t <sub>PLZ</sub>	xOE to xYx							
t <sub>SK(O)</sub>	Output Skew <sup>(2)</sup>	—	—	—	—	—	500	ps

- NOTES:**  
1. See TEST CIRCUITS AND WAVEFORMS. T<sub>A</sub> = - 40°C to + 85°C.  
2. Skew between any two outputs of the same package and switching in the same direction.

TEST CIRCUITS AND WAVEFORMS  
TEST CONDITIONS

Symbol	V <sub>CC</sub> <sup>(1)</sup> =3.3V±0.3V	V <sub>CC</sub> <sup>(1)</sup> =2.7V	V <sub>CC</sub> <sup>(2)</sup> =2.5V±0.2V	Unit
V <sub>LOAD</sub>	6	6	2 x V <sub>CC</sub>	V
V <sub>IH</sub>	2.7	2.7	V <sub>CC</sub>	V
V <sub>T</sub>	1.5	1.5	V <sub>CC</sub> / 2	V
V <sub>LZ</sub>	300	300	150	mV
V <sub>HZ</sub>	300	300	150	mV
C <sub>L</sub>	50	50	30	pF



Test Circuit for All Outputs

DEFINITIONS:

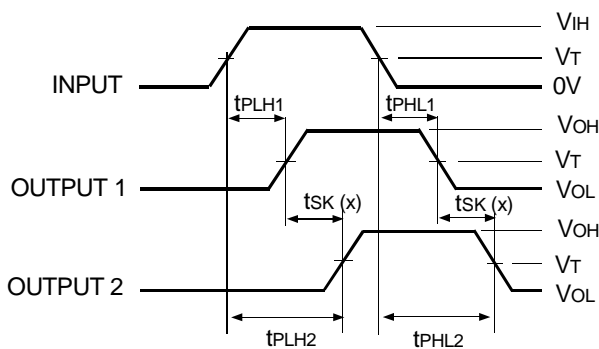
C<sub>L</sub> = Load capacitance: includes jig and probe capacitance.  
R<sub>T</sub> = Termination resistance: should be equal to Z<sub>OUT</sub> of the Pulse Generator.

NOTES:

1. Pulse Generator for All Pulses: Rate ≤ 10MHz; t<sub>r</sub> ≤ 2.5ns; t<sub>r</sub> ≤ 2.5ns.
2. Pulse Generator for All Pulses: Rate ≤ 10MHz; t<sub>r</sub> ≤ 2ns; t<sub>r</sub> ≤ 2ns.

SWITCH POSITION

Test	Switch
Open Drain Disable Low Enable Low	V <sub>LOAD</sub>
Disable High Enable High	GND
All Other Tests	Open

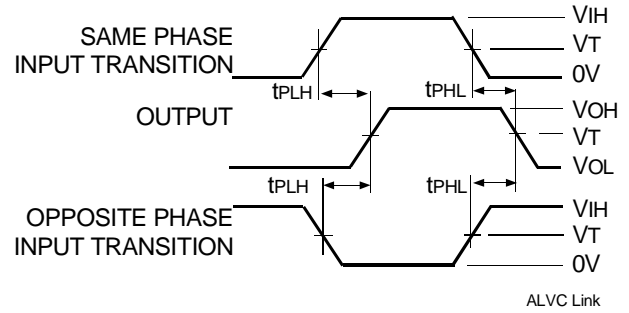


$$t_{SK}(x) = |t_{PLH2} - t_{PLH1}| \text{ or } |t_{PHL2} - t_{PHL1}|$$

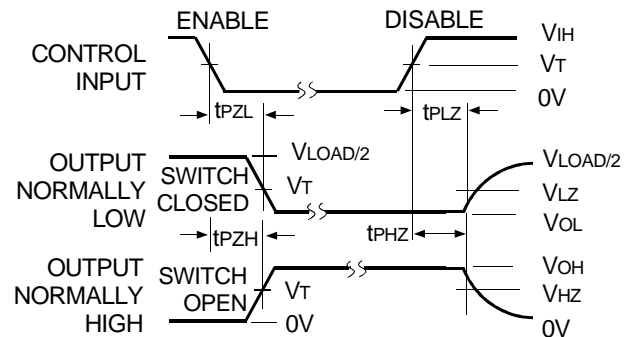
Output Skew - t<sub>SK</sub>(x)

NOTES:

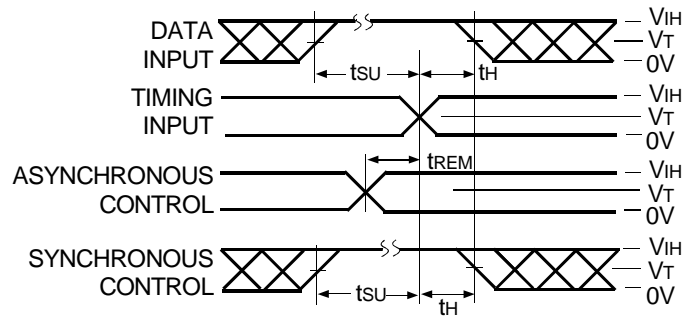
1. For t<sub>SK</sub>(o) OUTPUT1 and OUTPUT2 are any two outputs.
2. For t<sub>SK</sub>(b) OUTPUT1 and OUTPUT2 are in the same bank.



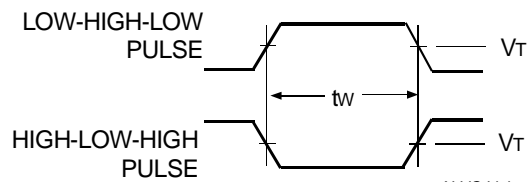
Propagation Delay



Enable and Disable Times

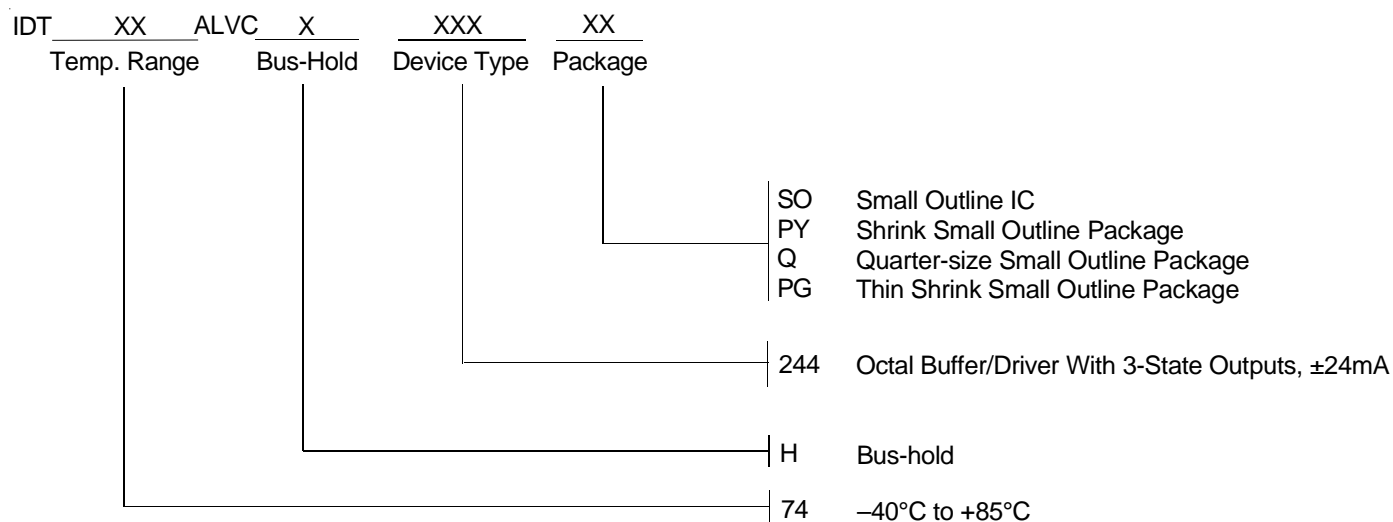


Set-up, Hold, and Release Times



Pulse Width

**ORDERING INFORMATION**



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